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Application/Control No.	Applicant(s)/Patent under Reexamination
10/604,546	SUN ET AL.
Examiner	Art Unit
TAN X. DINH	2627

	SEARCHED				
Class	Subclass	Date	Examiner		
720	659 660	6/14/2007	T.D		
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INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
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EAST (see search history printout)	6/14/2007	T.D
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